

# N-Channel 250 V (D-S) MOSFET

PRODUCT SUMMA	RY	
V <sub>DS</sub> (V)	250	)
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 \text{ V}$	2.0
Q <sub>g</sub> (Max.) (nC)	8.2	
Q <sub>gs</sub> (nC)	1.8	
Q <sub>gd</sub> (nC)	4.5	
Configuration	Sing	le

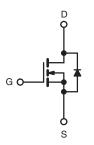
#### **FEATURES**

- Surface mount
- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- · Fast switching
- Ease of paralleling
- Simple drive requirements









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (To	c = 25 °C, un	less otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			$V_{DS}$	250	V
Gate-Source Voltage			$V_{GS}$	± 20	<b>∃</b> ′
Continuous Drain Current	V at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C		0.79	
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	0.50	Α
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	6.3	
Linear Derating Factor				0.025	W/°C
Linear Derating Factor (PCB Mount) <sup>e</sup>				0.017	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	50	mJ
Repetitive Avalanche Current a			А		
Repetitive Avalanche Energy a			mJ		
Maximum Power Dissipation	T <sub>C</sub> =	T <sub>C</sub> = 25 °C		3.1	w
Maximum Power Dissipation (PCB Mount) e	T <sub>A</sub> =	T <sub>A</sub> = 25 °C		2.0	v
Peak Diode Recovery dV/dt <sup>c</sup>	•		dV/dt	4.8	V/ns
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Soldering Recommendations (Peak Temperature)	d for	for 10 s		300	°C

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ ,  $L = 128 \,\text{mH}$ ,  $R_g = 25 \,^{\circ}\text{C}$ ,  $I_{AS} = 0.79 \,\text{A}$  (see fig. 12). c.  $I_{SD} \le 2.7 \,\text{A}$ ,  $I_{AS} = 0.79 \,\text{A}$ ,  $I_{AS} = 0.79 \,\text{A}$  (see fig. 12).
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	R <sub>thJA</sub>	-	-	60	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	-	40		

#### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static		<u> </u>			I.	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		250	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I <sub>D</sub> = 1 mA	-	0.39	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	٧
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zava Cata Valtaga Dvain Coverent	I <sub>DSS</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = 250 V, V <sub>GS</sub> = 0 V			25	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 200 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 0.47 A <sup>b</sup>	-	2.0	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> = 0.47 A	0.50	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V},$		140	-	pF
Output Capacitance	C <sub>oss</sub>				42	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	9.6	-	
Total Gate Charge	Qg		I <sub>D</sub> = 2.7 A, V <sub>DS</sub> = 200 V, see fig. 6 and 13 <sup>b</sup>	-	-	8.2	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	1.8	
Gate-Drain Charge	Q <sub>gd</sub>			-	-	4.5	
Turn-On Delay Time	t <sub>d(on)</sub>			-	7.0	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 125 V, $I_{D}$ = 2.7 A, $R_{g}$ = 24 $\Omega$ , $R_{D}$ = 45 $\Omega$ , see fig. 10 <sup>b</sup>		-	7.6	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	16	-	
Fall Time	t <sub>f</sub>			-	7.0	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	
Internal Source Inductance	L <sub>S</sub>			-	6.0	-	nH
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>		MOSFET symbol		-	0.79	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	showing the integral reverse p - n junction diode		-	-	6.3	А
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25  ^{\circ}\text{C},  I_S = 0.79  \text{A},  V_{GS} = 0  \text{V}^{ \text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 2.7 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s}^{\text{b}}$		-	190	390	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.64	1.3	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	on is dor	ninated b	v Le and	L <sub>D</sub> )	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq 300~\mu s;$  duty cycle  $\leq 2~\%.$



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

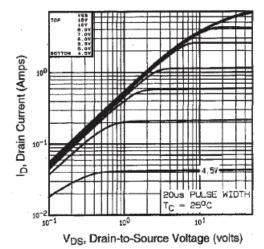


Fig. 1 - Typical Output Characteristics

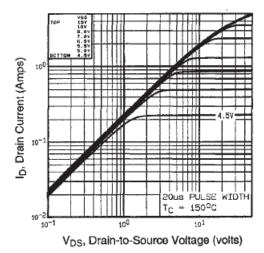


Fig. 2 - Typical Output Characteristics

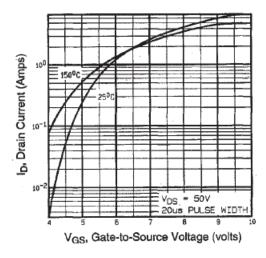


Fig. 3 - Typical Transfer Characteristics

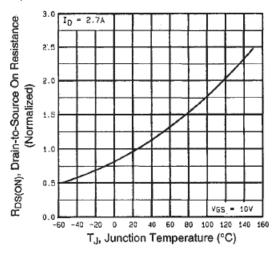


Fig. 4 - Normalized On-Resistance vs. Temperature

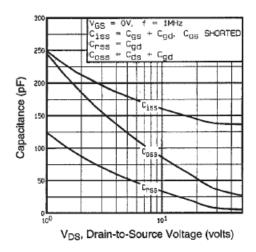


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

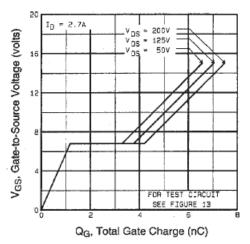


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



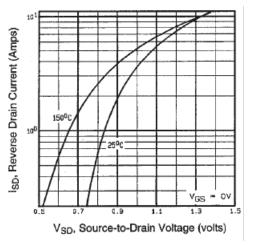


Fig. 7 - Typical Source-Drain Diode Forward Voltage

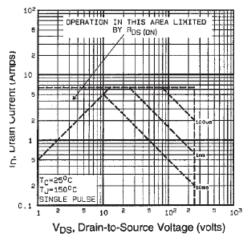


Fig. 8 - Maximum Safe Operating Area

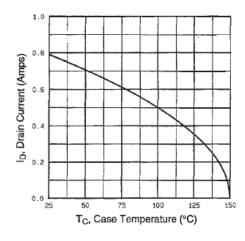


Fig. 9 - Maximum Drain Current vs. Case Temperature

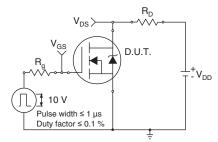


Fig. 10a - Switching Time Test Circuit

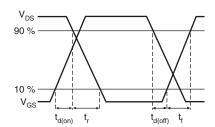


Fig. 10b - Switching Time Waveforms

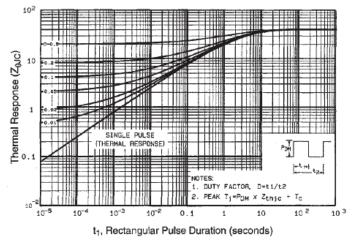


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



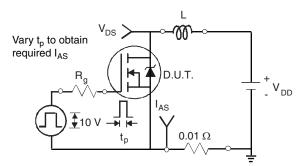


Fig. 12a - Unclamped Inductive Test Circuit

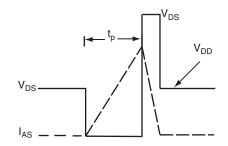


Fig. 12b - Unclamped Inductive Waveforms

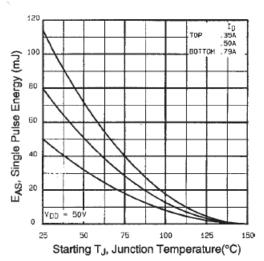


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

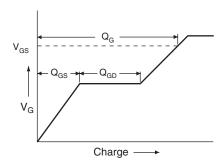


Fig. 13a - Basic Gate Charge Waveform

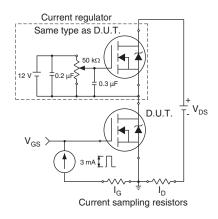
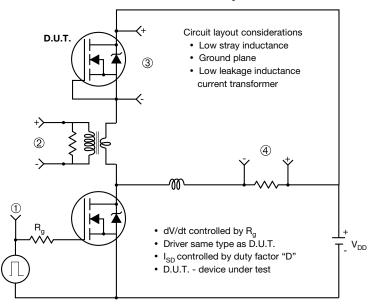


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



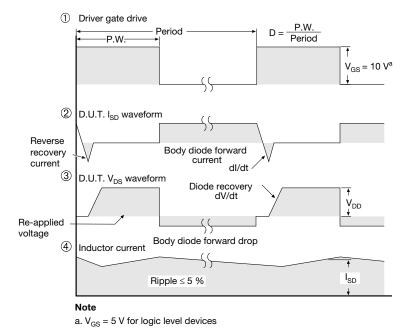
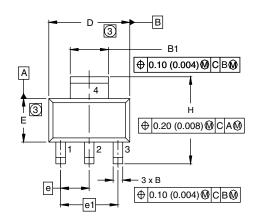
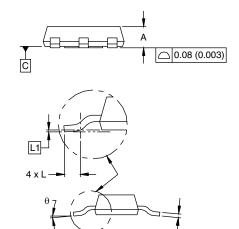


Fig.14 - For N-Channel



### **SOT-223 (HIGH VOLTAGE)**





DIM.	MILLI	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
Е	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181	BSC	
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.0024	BSC	
θ	-	10'	-	10'	

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.

服务热线:400-655-8788

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DMN2080UCB4-7 DMN61D9UWQ-13 US6M2GTR DMN31D5UDJ-7 DMP22D4UFO-7B DMN1006UCA6-7 DMN16M9UCA6-7
STF5N65M6 IRF40H233XTMA1 STU5N65M6 DMN6022SSD-13 DMN13M9UCA6-7 DMTH10H4M6SPS-13 DMN2990UFB-7B
IPB80P04P405ATMA2 2N7002W-G MCAC30N06Y-TP MCQ7328-TP BXP7N65D BXP4N65F AOL1454G WMJ80N60C4 BXP2N20L
BXP2N65D BXT1150N10J BXT1700P06M TSM60NB380CP ROG RQ7L055BGTCR DMNH15H110SK3-13 SLF10N65ABV2
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